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Minutes of the IEEE EMC Society  
Technical Committee on EMC Measurements and Instrumentation: TC-2  
August 27, 1998  
Adams Mark Hotel  
Denver, CO  
Members present:

Don Heirman, Chair  
Ed Bronaugh, Siemens  
John Osburn, EMC Test Systems

Members absent:

H. Benitez, Tektronix  
T. Hubing, U of Missouri-Rolla  
M. Jesse, ARC Professional Service Group  
D. Modi, Compatible Electronics  
J. Roman, Florida Atlantic University  
R. Roth, AMP, Inc.  
J. Speigelaar, AMP Inc.  
Tsaliovich, AT&T

Guests Present:

Jon Casemento, FDA  
Ron Fairley, Tektronix  
Mike Bogusz, Nortel

1. Call to Order:

The meeting was called to order by Chair Heirman at 8 am on August 27, 1998 at the Adams Mark Hotel, Denver, Colorado, the site of the 1998 EMC Symposium. The agenda is attachment A.

2. Acceptance of Previous Minutes

Minutes of the August 19, 1997 meeting in Austin, TX were approved as written

3. Committee Membership Status

As decided during the 1994 meeting, all guests attending each TC-2 meeting for the foreseeable future will automatically be added to the membership unless they indicate to the contrary. Attachment B is the latest membership list. The guests at this meeting will be added to the current membership list.

4. 1998 (Denver) Symposium Activity

TC-2 sponsored or was a primary contributor to the following session at the Denver Symposium:

Session T7: Fundamentals of EMC Measurements

TC-2 reviewed 41 abstracts for the symposium. Paper reviewers were:

Ed Bronaugh

Don Heirman  
Bob Hofmann  
Al Smith, Jr.

Attachment C is the cover letter emailed to the Technical Program Chairman on the results of the review.

5. New Standards Sponsorship

TC-2 continues to sponsor EMC standards activity:

Standard 213 (LISN construction)

Standard 299 (Shielding Effectiveness or Shielding Enclosures)

Standard 1128 (Evaluation of Absorbers)

Standard 1140 (Near E and H field Measurements for VDUs)

Standard 1302 (Gasketing Characterization)

Standard 1309 (Probe Calibration)

6. 1999 Seattle Symposium Activity Plans

1. Topics for Future Symposia

The committee reviewed the list of topics that might be suggested for Seattle and future symposia. The topics kept on the list are as follows (not in priority order):

- a. Component level testing versus full system testing
- b. Simultaneous measurements of radiated and conducted emissions
- c. Measurement of intentional radiators
- d. Measurement of effects of personal electronics aboard aircraft
- e. Manufacturing/production emission/immunity testing
- f. EMC measurement management
- g. IEC/ISO Guide 25 (draft Standard IEC/ISO Standard 17025)
- h. Specific absorption rate (SAR) measurements
- i. Measurements above and test site validation above 1 GHz

The committee is also willing to repeat its Basic EMC Measurements tutorial. This has been given 6 times since 1990. Space will be requested for Seattle. The same speakers will be asked to repeat their talks.

2. Technical Program Responsibilities

TC-2 will review abstracts for the Seattle symposium. The abstracts are due October 19, 1998 with the authors being notified of acceptance or rejection by 4 January 1999.

Camera-ready copies of the papers accepted are due by 8 March 1999.

3. 1999 Paper Review

See 6.2 above

4. New Membership Drive

As mentioned in 3.0 above, the membership mailing list is growing at each meeting by the addition of the names of all guests attending the meeting.

5. New Areas of Interest

See 6.1. There is continued coordination between the committee and the EMCS Standards Development Committee on measurement issues and sponsorship.

6. Basic EMC Measurement Training

See the minutes of the 1995 meeting for further information.

1. Next Meeting

The next meeting will be in Seattle. It will be a Continental breakfast meeting on August 4, 1999 at 8:00 am for a half hour.

2. Adjournment

The meeting adjourned at 8:45 am.

Respectfully submitted,  
D. N. Heirman, Chair